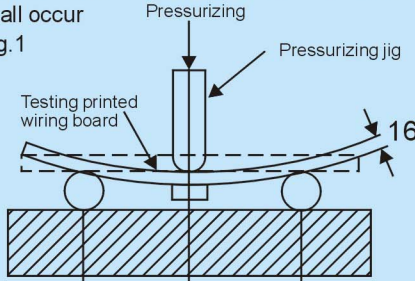
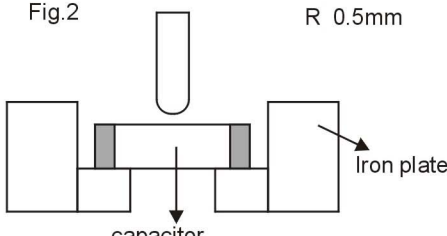


No	Item	Test Method	Specification	
15	Capacitance Temperature Characteristic	(a) NPO The temperature coefficient is determine during the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step 1 through 5. The capacitance shall be within the specified tolerance for the temperature coefficient.	Dielectric	
			Temperature Range	
			Capacitance Change	
			NPO	
			-55℃ to +125℃	
			0±60 ppm/℃	
			X7R	
	-55℃ to +125℃			
	Within 15%			
	X5R			
	-55℃ to +85℃			
	Within 15%			
	Z5U			
	+10℃ to +85℃			
	Within +22%~56%			
	Y5V			
	-30℃ to +85℃			
	Within +22%~82%			
16	Resistance to Board Bending	(b) X7R,X5R, Y5V,Z5U The ranges of capacitance change compared with the 25±2℃ value over the temperature range shall be within the specified ranges.	No cracking or marking defects shall occur	
			Unit:mm	
			Fig.1	
				
17	Chip Break Strength	Mount the capacitor to the testing print wiring board. Then apply force in the direction shown in Fig.1. The bending stroke shall be more than 1mm. Pressuring is carried out at the rate of 1mm/s. After reaching the specified bending. Keeping it for 5±1 seconds then measure the capacitance value. The capacitance could not be lower 5% of the initial value	To load 2 kg at least.	
			Fig.2	
			Φ 1.0mm	
			R 0.5mm	
				
			Iron plate	
			capacitor	
No	Item	Test Method	Specification	
18	Temperature Cycle	Mount the capacitor on test board, then cycling the temperature sequentially from step 1 to step 5, and perform 25 cycles.		
				No crack and electric failure